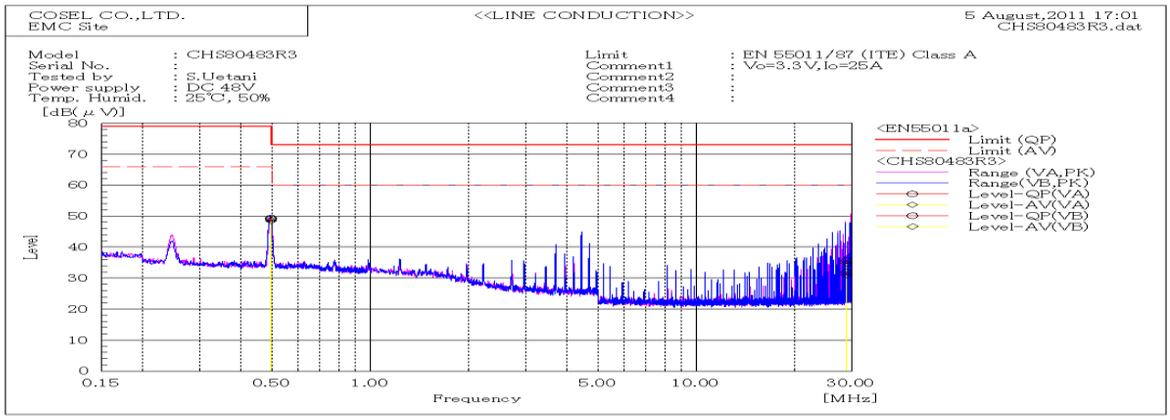
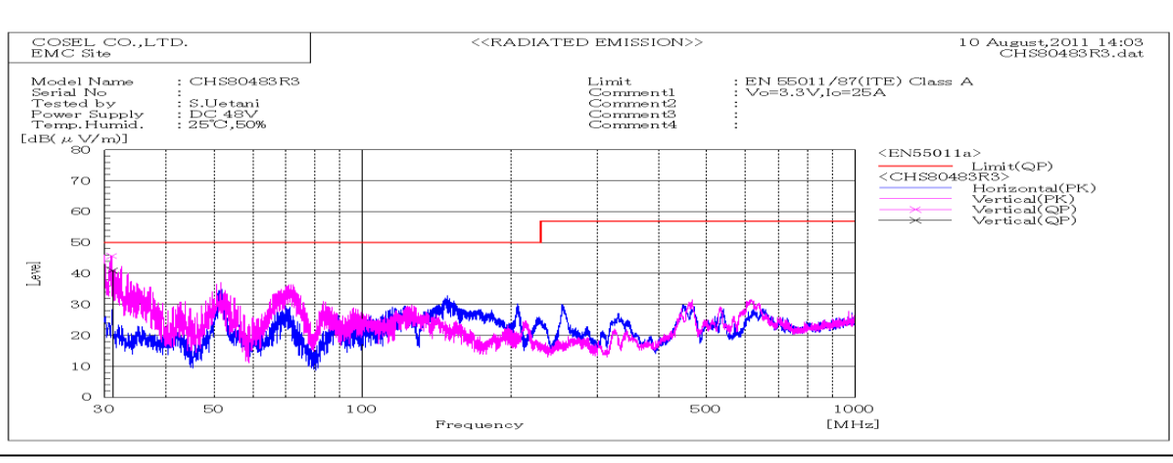
参考資料

COSEL

DATA SHEET		Date	27-Apr-21
Model	CHS80483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.49619		VA	39.4	38.8	10.1	49.5	48.9	79	66	29.5	17.1	Pass	
0.49609		VB	39	38.4	10.1	49.1	48.5	79	66	29.9	17.5	Pass	
28.8738		VA	24.7	23.7	11	35.7	34.7	73	60	37.3	25.3	Pass	
28.867		VB	20.9	20.1	11	31.9	31.1	73	60	41.1	28.9	Pass	

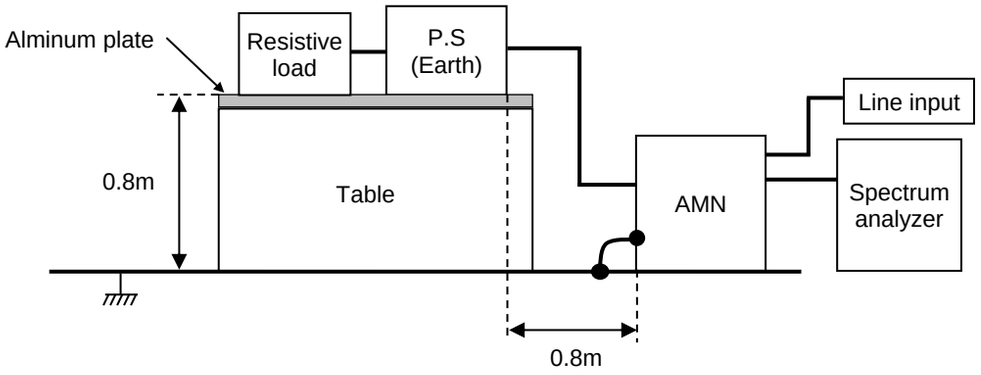


Frequency MHz	Harm	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				QP		QP	QP	QP				
31.129		V	Stable	55	-14	41	50	9	Pass	102	171	

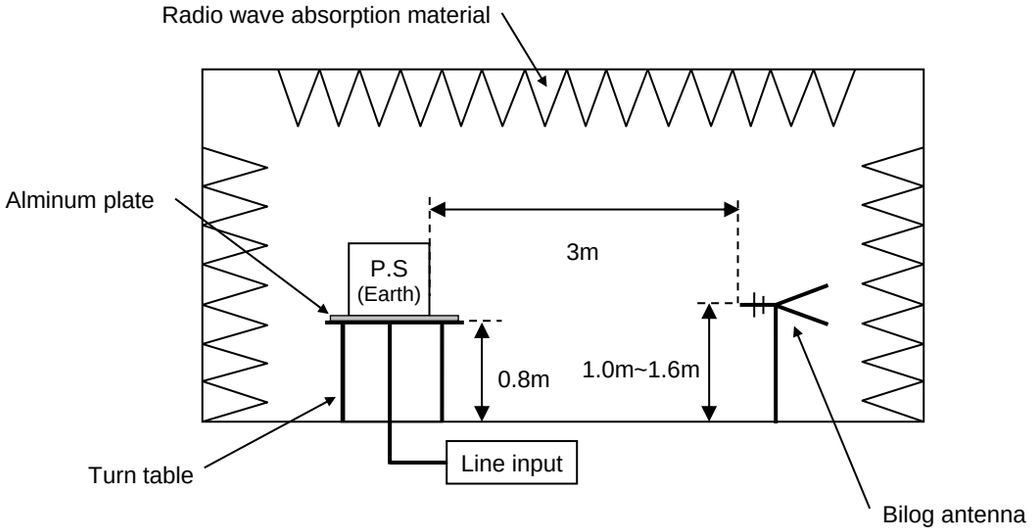
COSEL

DATA SHEET		Date	27-Apr-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani

1. Line conduction



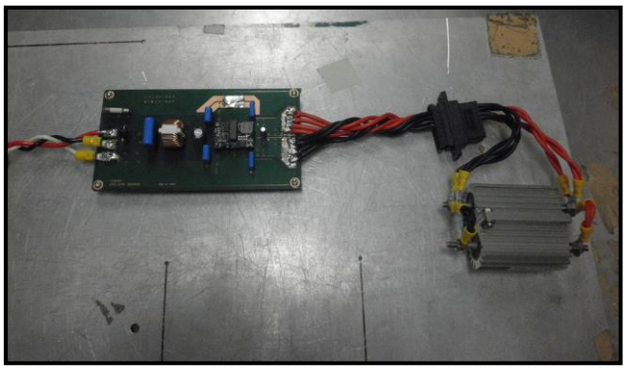
2. Radiated emission



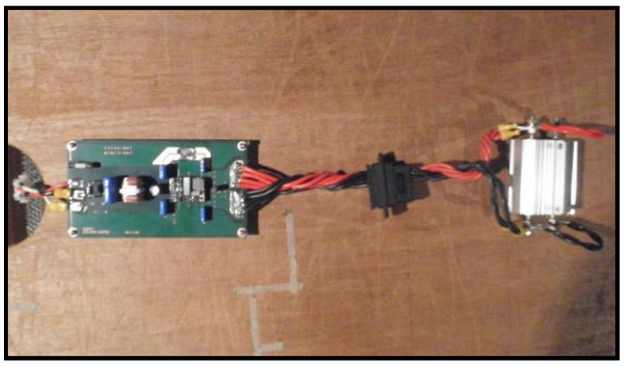
TEST :EMI
Model Name :CHS80483R3

Date 2011/10/4

○Photographs of Test Set-Up
LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

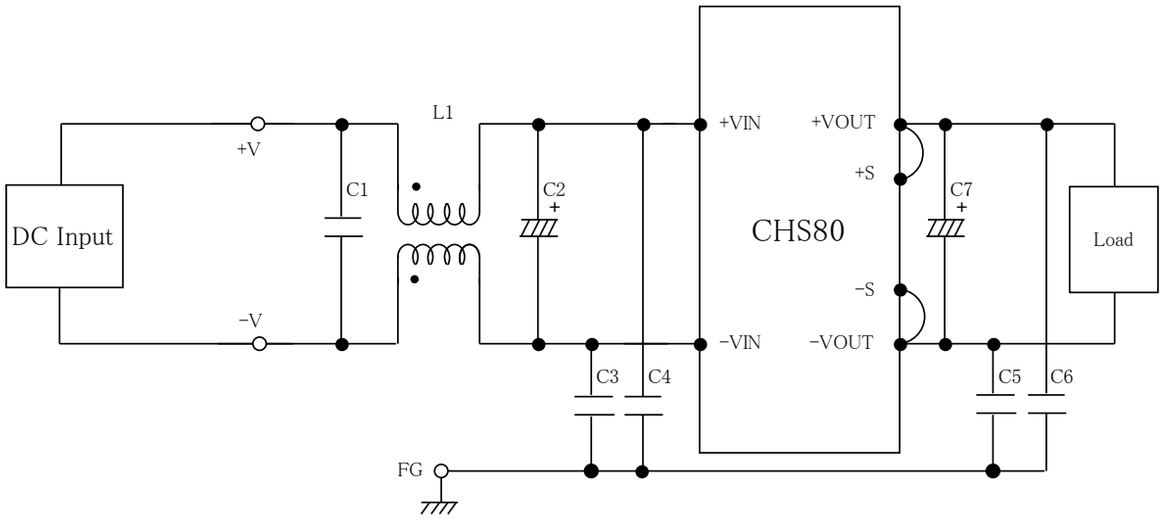


Fig.1 Testing circuitry

L1	:	1mH SC-05-10J (TOKIN)
C1	:	250V 2.2μF FPD22E225J4 (NITSUKO)
C2	:	100V 33μF PWseries (nichicon)
C3,C4	:	630V 0.068μF FPD22J683J4 (NITSUKO)
C5,C6	:	630V 0.033μF FPD22J333J4 (NITSUKO)
C7	:	50V 10μF PMseries (nichicon)